

FPM DRAM

MT4C1M16C3, MT4LC1M16C3

For the latest data sheet revisions, please refer to the Micron Website: www.micron.com/datasheets

FEATURES

- JEDEC- and industry-standard x16 timing, functions, pinouts, and packages
- High-performance, low-power CMOS silicon-gate process
- Single power supply (+3.3V ±0.3V or 5V ±0.5V)
- All inputs, outputs and clocks are TTL-compatible
- Refresh modes: RAS#-ONLY, CAS#-BEFORE-RAS# (CBR) and HIDDEN
- Optional self refresh (S) for low-power data retention
- BYTE WRITE and BYTE READ access cycles
- 1,024-cycle refresh (10 row, 10 column addresses)
- FAST-PAGE-MODE (FPM) access

OPTIONS

- Voltage¹

3.3V	LC
5V	C
- Packages

Plastic SOJ (400 mil)	DJ
Plastic TSOP (400 mil)	TG
- Timing

50ns access	-5
60ns access	-6
- Refresh Rates

Standard Refresh (16ms period)	None
Self Refresh (128ms period)	S ²
- Operating Temperature Range

Commercial (0°C to +70°C)	None
Extended (-20°C to +80°C)	ET ³

MARKING

Part Number Example:

MT4LC1M16C3DJ-5

NOTE: 1. The third field distinguishes the low voltage offering: LC designates Vcc = 3.3V and C designates Vcc = 5V.
2. Contact factory for availability.
3. Available only on MT4C1M16C3 (5V)

KEY TIMING PARAMETERS

SPEED	t _{RC}	t _{RAC}	t _{PC}	t _{AA}	t _{CAC}	t _{RP}
-5	84ns	50ns	20ns	25ns	15ns	30ns
-6	110ns	60ns	35ns	30ns	15ns	40ns

PIN ASSIGNMENT (Top View)

42-Pin SOJ

Vcc	1	42	Vss
DQ0	2	41	DQ15
DQ1	3	40	DQ14
DQ2	4	39	DQ13
DQ3	5	38	DQ12
Vcc	6	37	Vss
DQ4	7	36	DQ11
DQ5	8	35	DQ10
DQ6	9	34	DQ9
DQ7	10	33	DQ8
NC	11	32	NC
NC	12	31	CASL#
WE#	13	30	CASH#
RAS#	14	29	OE#
NC	15	28	A9
NC	16	27	A8
A0	17	26	A7
A1	18	25	A6
A2	19	24	A5
A3	20	23	A4
Vcc	21	22	Vss

44/50-Pin TSOP

Vcc	1	50	Vss
DQ0	2	49	DQ15
DQ1	3	48	DQ14
DQ2	4	47	DQ13
DQ3	5	46	DQ12
Vcc	6	45	Vss
DQ4	7	44	DQ11
DQ5	8	43	DQ10
DQ6	9	42	DQ9
DQ7	10	41	DQ8
NC	11	40	NC
NC	15	36	NC
NC	16	35	CASL#
WE#	17	34	CASH#
RAS#	18	33	OE#
NC	19	32	A9
NC	20	31	A8
A0	21	30	A7
A1	22	29	A6
A2	23	28	A5
A3	24	27	A4
Vcc	25	26	Vss

NOTE: The # symbol indicates signal is active LOW.

1 MEG x 16 FPM DRAM PART NUMBERS

PART NUMBER	SUPPLY	PACKAGE	REFRESH
MT4LC1M16C3DJ-6	3.3V	SOJ	Standard
MT4LC1M16C3DJ-6 S	3.3V	SOJ	Self
MT4LC1M16C3TG-6	3.3V	TSOP	Standard
MT4LC1M16C3TG-6 S	3.3V	TSOP	Self
MT4C1M16C3DJ-6	5V	SOJ	Standard
MT4C1M16C3TG-6	5V	TSOP	Standard

GENERAL DESCRIPTION

The 1 Meg x 16 DRAM is a randomly accessed, solid-state memory containing 16,777,216 bits organized in a x16 configuration. The 1 Meg x 16 DRAM has both BYTE WRITE and WORD WRITE access cycles via two CAS# pins (CASL# and CASH#). These function identically to a single CAS# on other DRAMs in that either CASL# or CASH# will generate an internal CAS#.

The CAS# function and timing are determined by the first CAS# (CASL# or CASH#) to transition LOW and

GENERAL DESCRIPTION (continued)

the last CAS# to transition back HIGH. Use of only one of the two results in a BYTE access cycle. CASL# transitioning LOW selects an access cycle for the lower byte (DQ0-DQ7), and CASH# transitioning LOW selects an access cycle for the upper byte (DQ8-DQ15).

Each bit is uniquely addressed through the 20 address bits during READ or WRITE cycles. These are entered ten bits (A0-A9) at a time. RAS# is used to latch the first ten bits and CAS# the latter ten bits. The CAS# function is determined by the first CAS# (CASL# or CASH#) to transition LOW and the last one to transition back HIGH. The CAS# function also determines whether the cycle will be a refresh cycle (RAS#-ONLY) or an active cycle (READ, WRITE, or READ-WRITE) once RAS# goes LOW.

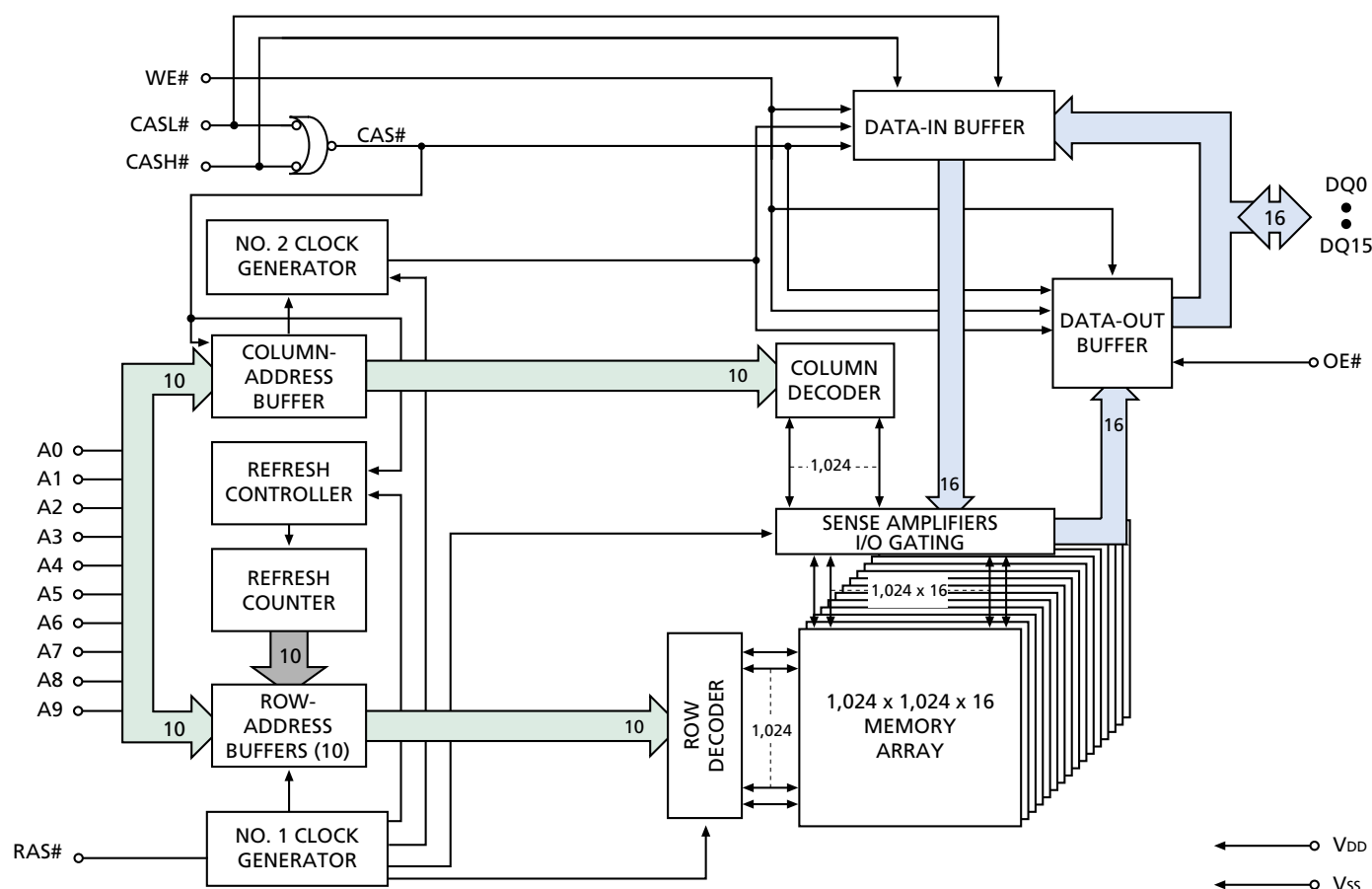
The CASL# and CASH# inputs internally generate a CAS# signal that functions identically to a single CAS# input on other DRAMs. The key difference is that each CAS# input (CASL# and CASH#) controls its corre-

sponding DQ tristate logic (in conjunction with OE# and WE#). CASL# controls DQ0-DQ7 and CASH# controls DQ8-DQ15. The two CAS# controls give the 1 Meg x 16 DRAM BYTE WRITE cycle capabilities.

A logic HIGH on WE# dictates read mode, while a logic LOW on WE# dictates write mode. During a WRITE cycle, data-in (D) is latched by the falling edge of WE# or CAS, whichever occurs last. Taking WE# LOW will initiate a WRITE cycle, selecting DQ0-DQ15. If WE# goes LOW prior to CAS# going LOW, the output pin(s) remain open (High-Z) until the next CAS# cycle. If WE# goes LOW after CAS# goes LOW and data reaches the output pins, data-out (Q) is activated and retains the selected cell data as long as CAS# and OE# remain LOW (regardless of WE# or RAS#). This late WE# pulse results in a READ-WRITE cycle.

The 16 data inputs and 16 data outputs are routed through 16 pins using common I/O. Pin direction is controlled by OE# and WE#.

FUNCTIONAL BLOCK DIAGRAM



GENERAL DESCRIPTION (continued)

The MT4LC1M16C3 must be refreshed periodically in order to retain stored data.

FAST PAGE MODE ACCESS

FAST-PAGE-MODE operations allow faster data operations (READ, WRITE or READ-MODIFY-WRITE) within a row-address-defined (A0-A9) page boundary. The FAST-PAGE-MODE cycle is always initiated with a row address strobed in by RAS#, followed by a column address strobed in by CAS#. Additional columns may be accessed by providing valid column addresses, strobing CAS# and holding RAS# LOW, thus executing faster memory cycles. Returning RAS# HIGH terminates the FAST-PAGE-MODE operation.

Returning RAS# and CAS# HIGH terminates a memory cycle and decreases chip current to a reduced standby level. The chip is also preconditioned for the next cycle during the RAS# HIGH time. Memory cell data is retained in its correct state by maintaining power

and executing any RAS# cycle (READ, WRITE) or RAS# REFRESH cycle (RAS# ONLY, CBR or HIDDEN) so that all 1,024 combinations of RAS# addresses (A0-A9) are executed at least every 16ms (128ms on the "S" version), regardless of sequence. The CBR REFRESH cycle will also invoke the refresh counter and controller for row-address control.

BYTE ACCESS CYCLE

The BYTE WRITES and BYTE READS are determined by the use of CASL# and CASH#. Enabling CASL# will select a lower byte access (DQ0-DQ7), while enabling CASH# will select an upper byte access (DQ0-DQ15). Enabling both CASL# and CASH# selects a WORD WRITE cycle.

The 1 Meg x 16 DRAM may be viewed as two 1 Meg x 8 DRAMs that have common input controls, with the exception of the CAS# inputs. Figure 1 illustrates the BYTE WRITE and WORD WRITE cycles. Figure 2 illustrates BYTE READ and WORD READ cycles.

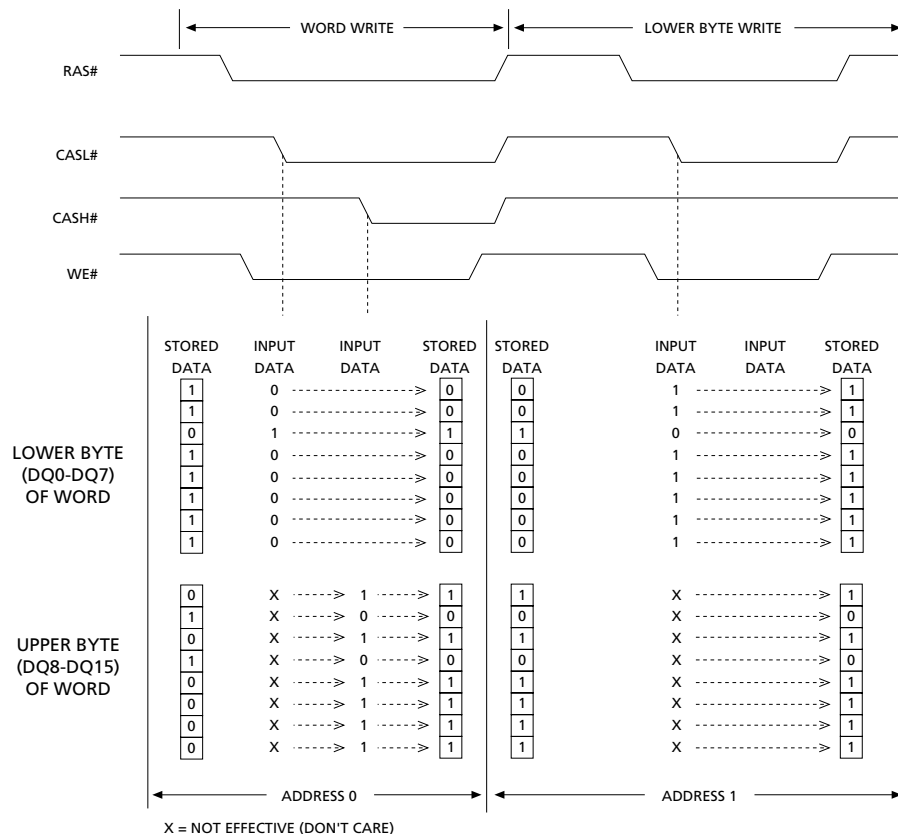


Figure 1
WORD and BYTE WRITE Example

Additionally, both bytes must always be of the same mode of operation if both bytes are active. A CAS# precharge must be satisfied prior to changing modes of operation between the upper and lower bytes. For example, an EARLY WRITE on one byte and a LATE WRITE on the other byte are not allowed during the same cycle. However, an EARLY WRITE on one byte and a LATE WRITE on the other byte, after a CAS# precharge has been satisfied, are permissible.

DRAM REFRESH

Preserve correct memory cell data by maintaining power and executing any RAS# cycle (READ, WRITE) or RAS# REFRESH cycle (RAS#-ONLY, CBR or HIDDEN) so that all 1,024 combinations of RAS# addresses are executed within $t_{REF}^{(MAX)}$, regardless of sequence. The CBR and EXTENDED and SELF REFRESH cycles will invoke the internal refresh counter for automatic RAS# addressing.

An optional self refresh mode is available on the "S" version. The self refresh feature is initiated by performing a CBR REFRESH cycle and holding RAS# LOW for the specified t_{RASS} . The "S" option allows the user

the choice of a fully static, low-power data retention mode or a dynamic refresh mode at the extended refresh period of 128ms, or 125 μ s per row, when using a distributed CBR REFRESH. This refresh rate can be applied during normal operation, as well as during a standby or battery backup mode.

The self refresh mode is terminated by driving RAS# HIGH for a minimum time of t_{RPS} . This delay allows for the completion of any internal refresh cycles that may be in process at the time of the RAS# LOW-to-HIGH transition. If the DRAM controller uses a distributed CBR refresh sequence, a burst refresh is not required upon exiting self refresh. However, if the DRAM controller utilizes a RAS#-ONLY or burst CBR refresh sequence, all 1,024 rows must be refreshed using a minimum t_{RC} refresh rate prior to resuming normal operation.

STANDBY

Returning RAS# and CAS# HIGH terminates a memory cycle and decreases chip current to a reduced standby level. The chip is preconditioned for the next cycle during the RAS# HIGH time.

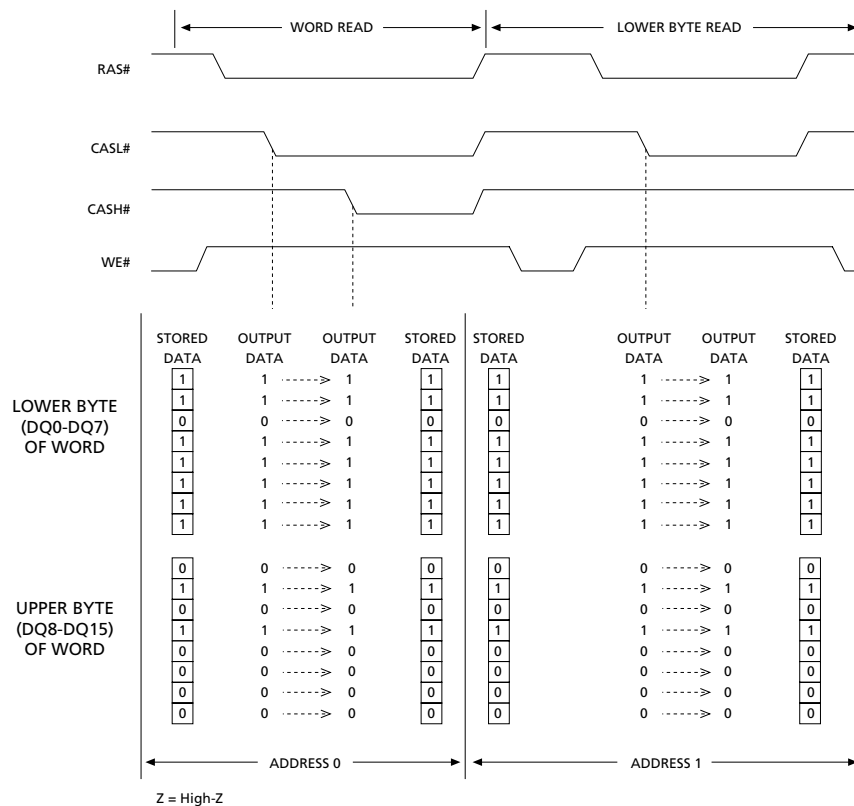


Figure 2
WORD and BYTE READ Example

ABSOLUTE MAXIMUM RATINGS*

Voltage on V _{CC} Pin Relative to V _{SS}	
3.3V	-1V to +4.6V
5V	-1V to +7V
Voltage on NC, Inputs or I/O Pins Relative to V _{SS}	
3.3V	-1V to +5.5V
5V	-1V to +7V
Operating Temperature	
T _A (commercial)	0°C to +70°C
T _A (extended "ET")	-20°C to +80°C
Storage Temperature (plastic)	
Power Dissipation	
1W	

*Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

DC ELECTRICAL CHARACTERISTICS AND OPERATING CONDITIONS

(Notes: 1, 5, 6; notes can be found on page 9); V_{CC} (MIN) ≤ V_{CC} ≤ V_{CC} (MAX)

PARAMETER/CONDITION	SYMBOL	3.3V		5V		UNITS	NOTES
		MIN	MAX	MIN	MAX		
SUPPLY VOLTAGE	V _{CC}	3	3.6	4.5	5.5	V	
INPUT HIGH VOLTAGE: Valid Logic 1; All inputs, I/Os and any NC	V _{IH}	2	5.5	2.4	V _{CC} + 1	V	
INPUT LOW VOLTAGE: Valid Logic 0; All inputs, I/Os and any NC	V _{IL}	-1.0	0.8	-0.5	0.8	V	
INPUT LEAKAGE CURRENT: Any input at V _{IN} (0V ≤ V _{IN} ≤ V _{CC} + 0.3V); All other pins not under test = 0V	I _I	-2	2	-2	2	μA	
OUTPUT HIGH VOLTAGE: I _{OUT} = -2mA	V _{OH}	2.4	–	2.4	–	V	
OUTPUT LOW VOLTAGE: I _{OUT} = 2mA	V _{OL}	–	0.4	–	0.4	V	
OUTPUT LEAKAGE CURRENT: Any output at V _{OUT} [0V ≤ V _{OUT} ≤ V _{CC} (MAX)]; DQ is disabled and in High-Z state	I _{OZ}	-5	5	-5	5	μA	

I_{CC} OPERATING CONDITIONS AND MAXIMUM LIMITS

(Notes: 1, 2, 3, 5, 6; notes can be found on page 9); $V_{CC} (MIN) \leq V_{CC} \leq V_{CC} (MAX)$

PARAMETER/CONDITION	SYMBOL	SPEED	3.3V	5V	UNITS	NOTES
STANDBY CURRENT: TTL (RAS# = CAS# = V _{IH})	I _{CC1}	ALL	1	2	mA	
STANDBY CURRENT: CMOS (non-"S" version only) (RAS# = CAS# = other inputs = V _{CC} - 0.2V)	I _{CC2}	ALL	500	500	μA	
STANDBY CURRENT: CMOS ("S" version only) (RAS# = CAS# = other inputs = V _{CC} - 0.2V)	I _{CC2}	ALL	150	150	μA	
OPERATING CURRENT: Random READ/WRITE Average power supply current (RAS#, CAS#, address cycling: t _{RC} = t _{RC} [MIN])	I _{CC3}	-5 -6	180 170	190 180	mA	23
OPERATING CURRENT: FAST PAGE MODE Average power supply current (RAS# = V _{IL} , CAS#, address cycling: t _{PC} = t _{PC} [MIN])	I _{CC4}	-5 -6	110 90	120 110	mA	23
REFRESH CURRENT: RAS#-ONLY Average power supply current (RAS# cycling, CAS# = V _{IH} : t _{RC} = t _{RC} [MIN])	I _{CC5}	-5 -6	180 170	190 180	mA	
REFRESH CURRENT: CBR Average power supply current (RAS#, CAS#, address cycling: t _{RC} = t _{RC} [MIN])	I _{CC6}	-5 -6	180 170	180 180	mA	4, 7
REFRESH CURRENT: Extended ("S" version only) Average power supply current: CAS# = 0.2V or CBR cycling; RAS# = t _{RAS} (MIN); WE# = V _{CC} - 0.2V; A0-A11, OE# and D _{IN} = V _{CC} - 0.2V or 0.2V (D _{IN} may be left open)	I _{CC7}	ALL	300	300	μA	4, 7
REFRESH CURRENT: Self ("S" version only) Average power supply current: CBR with RAS# t _{RAS} (MIN) and CAS# held LOW; WE# = V _{CC} - 0.2V; A0-A11, OE# and D _{IN} = V _{CC} - 0.2V or 0.2V (D _{IN} may be left open)	I _{CC8}	ALL	300	300	μA	4, 7

CAPACITANCE

(Note: 2; notes can be found on page 9);

PARAMETER	SYMBOL	MAX	UNITS
Input Capacitance: Addresses	C _{I1}	5	pF
Input Capacitance: RAS#, CASL#, CASH#, WE#, OE#	C _{I2}	7	pF
Input/Output Capacitance: DQ	C _{IO}	7	pF

AC ELECTRICAL CHARACTERISTICS

(Notes: 5, 6, 7, 8, 9, 10, 11, 12; notes can be found on page 9); $V_{CC} (MIN) \leq V_{CC} \leq V_{CC} (MAX)$

AC CHARACTERISTICS		-5		-6		UNITS	NOTES
PARAMETER	SYMBOL	MIN	MAX	MIN	MAX		
Access time from column address	t_{AA}		25		30	ns	
Column-address hold time (referenced to RAS#)	t_{AR}	38		45		ns	
Column-address setup time	t_{ASC}	0		0		ns	27
Row-address setup time	t_{ASR}	0		0		ns	
Column address to WE# delay time	t_{AWD}	42		49		ns	18
Access time from CAS	t_{CAC}		15		15	ns	29
Column-address hold time	t_{CAH}	8		10		ns	27
CAS# pulse width	t_{CAS}	8	10,000	10	10,000	ns	32, 35
CAS# LOW to "Don't Care" during Self Refresh	t_{CHD}	15		15		ns	
CAS# hold time (CBR Refresh)	t_{CHR}	8		10		ns	4, 28
Last CAS# going LOW to first CAS# to return HIGH	t_{CLCH}	10		10		ns	30
CAS# to output in Low-Z	t_{CLZ}	0		0		ns	26, 29
CAS# precharge time	t_{CP}	8		5		ns	30
Access time from CAS# precharge	t_{CPA}		28		35	ns	28
CAS# to RAS# precharge time	t_{CRP}	5		5		ns	28
CAS# hold time	t_{CSH}	38		45		ns	28
CAS# setup time (CBR Refresh)	t_{CSR}	5		5		ns	4, 27
CAS# to WE# delay time	t_{CWD}	28		35		ns	18, 27
WRITE command to CAS# lead time	t_{CWL}	8		10		ns	23, 29
Data-in hold time	t_{DH}	8		10		ns	19, 29
Data-in setup time	t_{DS}	0		0		ns	19, 29
Output disable	t_{OD}	0	12	0	15	ns	17, 26, 29
Output enable	t_{OE}		12		15	ns	22
OE# hold time from WE# during READ-MODIFY-WRITE cycle	t_{OEH}	8		10		ns	20
Output buffer turn-off delay	t_{OFF}	0	12	0	15	ns	11, 17, 23
OE# setup prior to RAS# during HIDDEN Refresh cycle	t_{ORD}	0		0		ns	
FAST-PAGE-MODE READ or WRITE cycle time	t_{PC}	20		25		ns	31
FAST-PAGE-MODE READ-WRITE cycle time	t_{PRWC}	47		56		ns	31
Access time from RAS#	t_{RAC}		50		60	ns	
RAS# to column-address delay time	t_{RAD}	9		12		ns	20
Row-address hold time	t_{RAH}	9		10		ns	
RAS# pulse width	t_{RAS}	50	10,000	60	10,000	ns	
RAS# pulse width (FAST PAGE MODE)	t_{RASP}	50	125,000	60	125,000	ns	
RAS# pulse width (Self Refresh)	t_{RASS}	100		100		μs	
Random READ or WRITE cycle time	t_{RC}	84		104		ns	
RAS# to CAS# delay time	t_{RCD}	11		14		ns	14, 27
READ command hold time (referenced to CAS)	t_{RCH}	0		0		ns	16, 28
READ command setup time	t_{RCS}	0		0		ns	27
Refresh period (1,024 cycles)	t_{REF}		16		16	ms	
Refresh period (1,024 cycles) "S" version	t_{REF}		128		128	ms	
RAS# precharge time	t_{RP}	30		40		ns	
RAS# to CAS# precharge time	t_{RPC}	5		5		ns	
RAS# precharge time (Self Refresh)	t_{RPS}	90		105		ns	
READ command hold time (referenced to RAS#)	t_{RRH}	0		0		ns	16
RAS# hold time	t_{RSH}	13		15		ns	36
READ-WRITE cycle time	t_{RWC}	116		140		ns	

AC ELECTRICAL CHARACTERISTICS

(Notes: 5, 6, 7, 8, 9, 10, 11, 12; notes can be found on page 9); $V_{CC} (MIN) \leq V_{CC} \leq V_{CC} (MAX)$

AC CHARACTERISTICS		-5		-6			
PARAMETER	SYMBOL	MIN	MAX	MIN	MAX	UNITS	NOTES
RAS# to WE# delay time	t_{RWD}	67		79		ns	18
WRITE command to RAS# lead time	t_{RWL}	13		15		ns	
Transition time (rise or fall)	t_T	2	50	2	50	ns	
WRITE command hold time	t_{WCH}	8		10		ns	36
WRITE command hold time (referenced to RAS#)	t_{WCR}	38		45		ns	
WE# command setup time	t_{WCS}	0		0		ns	18, 27
WRITE command pulse width	t_{WP}	5		5		ns	
WE# hold time (CBR Refresh)	t_{WRH}	8		10		ns	
WE# setup time (CBR Refresh)	t_{WRP}	8		10		ns	

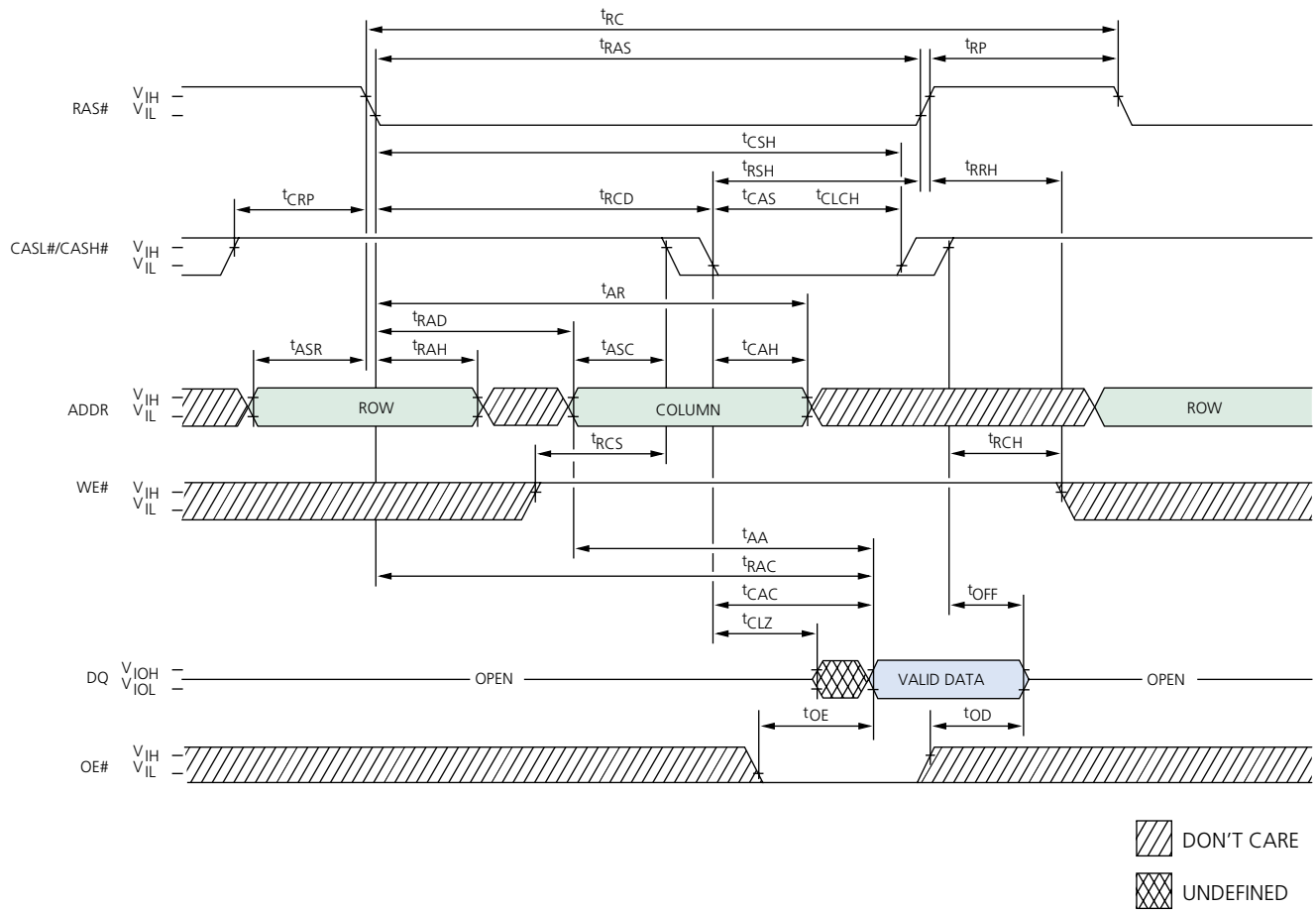
NOTES

1. All voltages referenced to V_{SS} .
2. This parameter is sampled. $V_{CC} = +3.3V$ or $5.0V$; $f = 1\text{ MHz}$.
3. I_{CC} is dependent on output loading. Specified values are obtained with minimum cycle time and the output open.
4. Enables on-chip refresh and address counters.
5. The minimum specifications are used only to indicate cycle time at which proper operation over the full temperature range ($0^{\circ}\text{C} \leq T_A \leq 70^{\circ}\text{C}$) for commercial and ($-20^{\circ}\text{C} \leq T_A \leq 80^{\circ}\text{C}$) for extended "ET" is ensured.
6. An initial pause of $100\mu\text{s}$ is required after power-up, followed by eight RAS# refresh cycles (RAS#-ONLY or CBR), before proper device operation is ensured. The eight RAS# cycle wake-ups should be repeated any time the t_{REF} refresh requirement is exceeded.
7. AC characteristics assume $t_T = 5\text{ ns}$.
8. V_{IH} (MIN) and V_{IL} (MAX) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} and V_{IL} (or between V_{IL} and V_{IH}).
9. In addition to meeting the transition rate specification, all input signals must transit between V_{IH} and V_{IL} (or between V_{IL} and V_{IH}) in a monotonic manner.
10. If $CAS\# = V_{IH}$, data output is High-Z.
11. If $CAS\# = V_{IL}$, data output may contain data from the last valid READ cycle.
12. Measured with a load equivalent to two TTL gates, 100 pF and $V_{OL} = 0.8V$ and $V_{OH} = 2V$.
13. If $CAS\#$ is LOW at the falling edge of RAS#, Q will be maintained from the previous cycle. To initiate a new cycle and clear the Q buffer, $CAS\#$ must be pulsed HIGH for t_{CP} .
14. The t_{RCD} (MAX) limit is no longer specified. t_{RCD} (MAX) was specified as a reference point only. If t_{RCD} was greater than the specified t_{RCD} (MAX) limit, then access time was controlled exclusively by t_{CAC} (t_{RAC} [MIN] no longer applied). With or without the t_{RCD} limit, t_{AA} and t_{CAC} must always be met.
15. The t_{RAD} (MAX) limit is no longer specified. t_{RAD} (MAX) was specified as a reference point only. If t_{RAD} was greater than the specified t_{RAD} (MAX) limit, then access time was controlled exclusively by t_{AA} (t_{RAC} and t_{CAC} no longer applied). With or without the t_{RAD} (MAX) limit, t_{AA} , t_{RAC} , and t_{CAC} must always be met.
16. Either t_{RCH} or t_{RRH} must be satisfied for a READ cycle.
17. t_{OFF} (MAX) defines the time at which the output achieves the open circuit condition; it is not a reference to V_{OH} or V_{OL} .
18. t_{WCS} , t_{RWD} , t_{AWD} , and t_{CWD} are restrictive operating parameters in LATE WRITE and READ-MODIFY-WRITE cycles only. If $t_{WCS} \geq t_{WCS}$ (MIN), the cycle is an EARLY WRITE cycle and the data out-put will remain an open circuit throughout the entire cycle. If $t_{RWD} \geq t_{RWD}$ (MIN), $t_{AWD} \geq t_{AWD}$ (MIN) and $t_{CWD} \geq t_{CWD}$ (MIN), the cycle is a READ WRITE and the data output will contain data read from the selected cell. If neither of the above conditions is met, the state of Q (at access time and until $CAS\#$ or $OE\#$ goes back to V_{IH}) is indeterminate. $OE\#$ held HIGH and $WE\#$ taken LOW after $CAS\#$ goes LOW result in a LATE WRITE ($OE\#$ -controlled) cycle.
19. These parameters are referenced to $CAS\#$ leading edge in EARLY WRITE cycles and $WE\#$ leading edge in LATE WRITE or READ-MODIFY-WRITE cycles.
20. During a READ cycle, if $OE\#$ is LOW then taken HIGH before $CAS\#$ goes HIGH, Q goes open. If $OE\#$ is tied permanently LOW, LATE WRITE and READ-MODIFY-WRITE operations are not permissible and should not be attempted.
21. A HIDDEN REFRESH may also be performed after a WRITE cycle. In this case, $WE\# = \text{LOW}$ and $OE\# = \text{HIGH}$.
22. All other inputs at $0.2V$ or $V_{CC} - 0.2V$.
23. Column address changed once each cycle.
24. LATE WRITE and READ-MODIFY-WRITE cycles must have both t_{OD} and $t_{OE\#}$ met ($OE\#$ HIGH during WRITE cycle) in order to ensure that the output buffers will be open during the WRITE cycle. The DQs will provide the previously read data if $CAS\#$ remains LOW and $OE\#$ is taken back LOW after $t_{OE\#}$ is met. If $CAS\#$ goes HIGH prior to $OE\#$ going back LOW, the DQs will remain open.
25. The DQs open during READ cycles once t_{OD} or t_{OFF} occur.
26. The 3 ns minimum is a parameter guaranteed by design.
27. The first $CASx$ edge to transition LOW.
28. The last $CASx$ edge to transition HIGH.
29. Output parameter (DQx) is referenced to corresponding $CAS\#$ input; DQ0-DQ7 by $CASL\#$ and DQ8-DQ15 by $CASH\#$.
30. Last falling $CASx$ edge to first rising $CASx$ edge.
31. Last rising $CASx$ edge to next cycle's last rising $CASx$ edge.

NOTES (continued)

- 32. Last rising CASx edge to first falling CASx edge.
- 33. First DQs controlled by the first CASx to go LOW.
- 34. Last DQs controlled by the last CASx to go HIGH.
- 35. Each CASx must meet minimum pulse width.
- 36. Last CASx to go LOW.
- 37. All DQs controlled, regardless CASL# and CASH#.
- 38. If OE# is tied permanently LOW, LATE WRITE, or READ-MODIFY-WRITE operations are not permissible and should not be attempted.

READ CYCLE

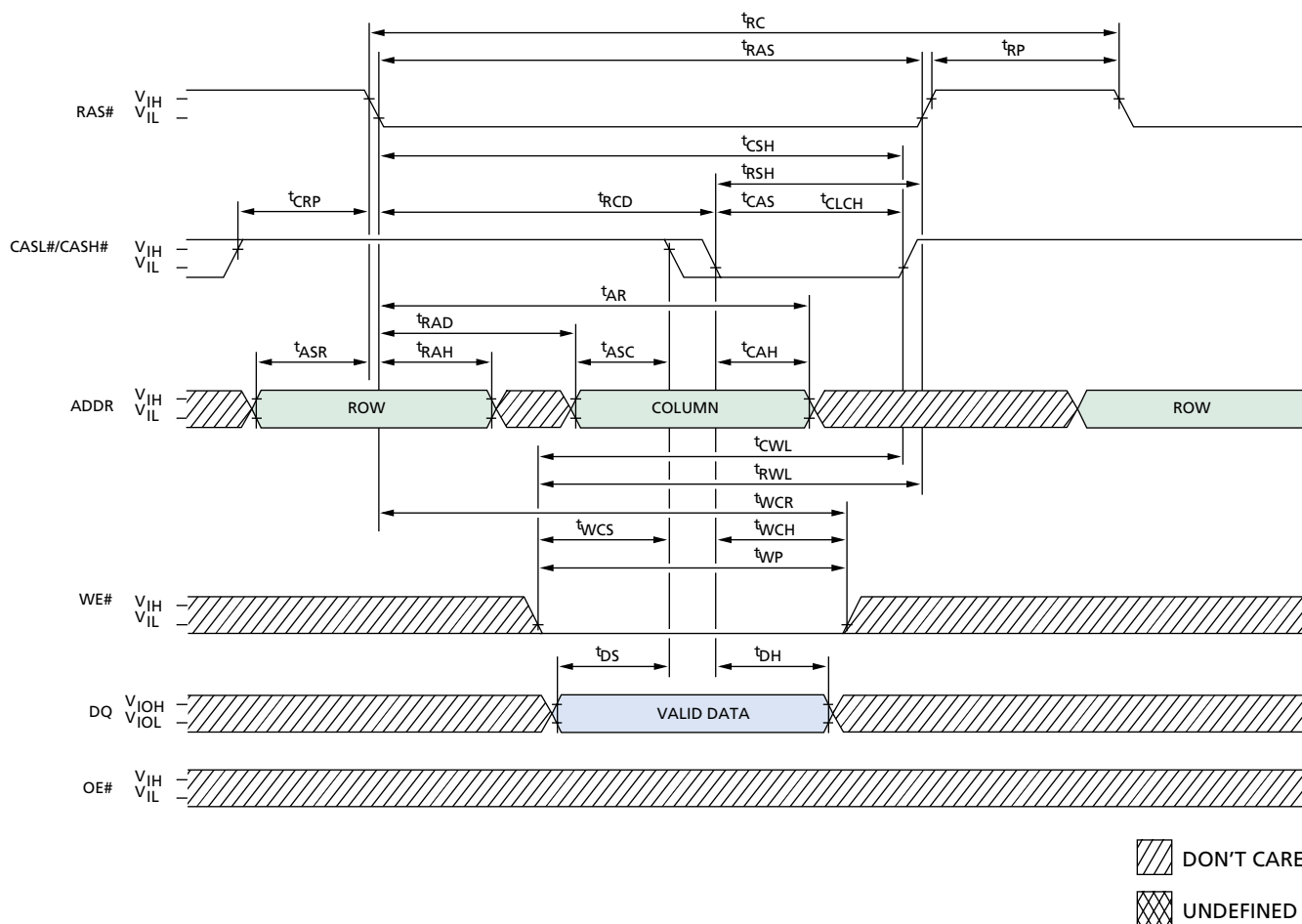


TIMING PARAMETERS

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{AA}		25		30	ns
t_{AR}	38		45		ns
t_{ASC}	0		0		ns
t_{ASR}	0		0		ns
t_{CAC}		15		15	ns
t_{CAH}	8		10		ns
t_{CAS}	8	10,000	10	10,000	ns
t_{CLCH}	10		10		ns
t_{CLZ}	0		0		ns
t_{CRP}	5		5		ns
t_{CSH}	38		45		ns
t_{OD}	0	12	0	15	ns
t_{OE}		12		15	ns

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{OFF}	0	12	0	15	ns
t_{RAC}		50		60	ns
t_{RAD}	9		12		ns
t_{RAH}	9		10		ns
t_{RAS}	50	10,000	60	10,000	ns
t_{RC}	84		104		ns
t_{RCD}	11		14		ns
t_{RCH}	0		0		ns
t_{RCS}	0		0		ns
t_{RP}	30		40		ns
t_{RRH}	0		0		ns
t_{RSH}	13		15		ns

EARLY WRITE CYCLE



TIMING PARAMETERS

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{AR}	38		45		ns
t_{ASC}	0		0		ns
t_{ASR}	0		0		ns
t_{CAH}	8		10		ns
t_{CAS}	8	10,000	10	10,000	ns
t_{CLCH}	10		10		ns
t_{CRP}	5		5		ns
t_{CSH}	38		45		ns
t_{CWL}	8		10		ns
t_{DH}	8		10		ns
t_{DS}	0		0		ns
t_{RAD}	9		12		ns

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{RAH}	9		10		ns
t_{RAS}	50	10,000	60	10,000	ns
t_{RC}	84		104		ns
t_{RCD}	11		14		ns
t_{RP}	30		40		ns
t_{RSH}	13		15		ns
t_{RWL}	13		15		ns
t_{WCH}	8		10		ns
t_{WCR}	38		45		ns
t_{WCS}	0		0		ns
t_{WP}	5		5		ns

The diagram illustrates the timing relationships between several control and data signals in a DDR3 SDRAM system:

- RAS#**: Row Address Strobe. Active low signal. Timing parameters include t_{RAS} (pulse width), t_{CRP} (setup before CAS#), t_{AR} (access time from RAS# to data valid), t_{RAH} (hold after RAS#), and t_{ASC} (setup before column address).
- CAS#/CASH#**: Column Address Strobe / Command Address Strobe. Active low signal. Timing parameters include t_{CSH} (setup before RAS#), t_{RSH} (hold after RAS#), t_{RCD} (read command delay), t_{CAS} (column access time), t_{CLCH} (clock-to-output delay), and t_{CAH} (hold after column address).
- ADDR**: Address bus. Shows **ROW** and **COLUMN** phases. Timing parameters include t_{ASR} (setup before RAS#), t_{RAD} (read array delay), t_{ASC} (setup before column address), and t_{CAH} (hold after column address).
- WE#**: Write Enable. Active low signal. Timing parameters include t_{AA} (array access time), t_{RAC} (refresh access time), t_{CAC} (cache access time), t_{RCS} (read command setup), t_{CWD} (write data delay), t_{AWD} (write array delay), t_{WP} (write pulse width), t_{RWL} (read word latency), and t_{CWL} (write word latency).
- DQ**: Data bus. Shows **VALID D_{OUT}** and **VALID D_{IN}** periods. Timing parameters include t_{OE} (output enable delay), t_{OD} (output delay), t_{OEHL} (output enable hold), t_{DS} (data setup), and t_{DH} (data hold).
- OE#**: Output Enable. Active low signal. Timing parameters include t_{OE} (output enable delay) and t_{OEHL} (output enable hold).

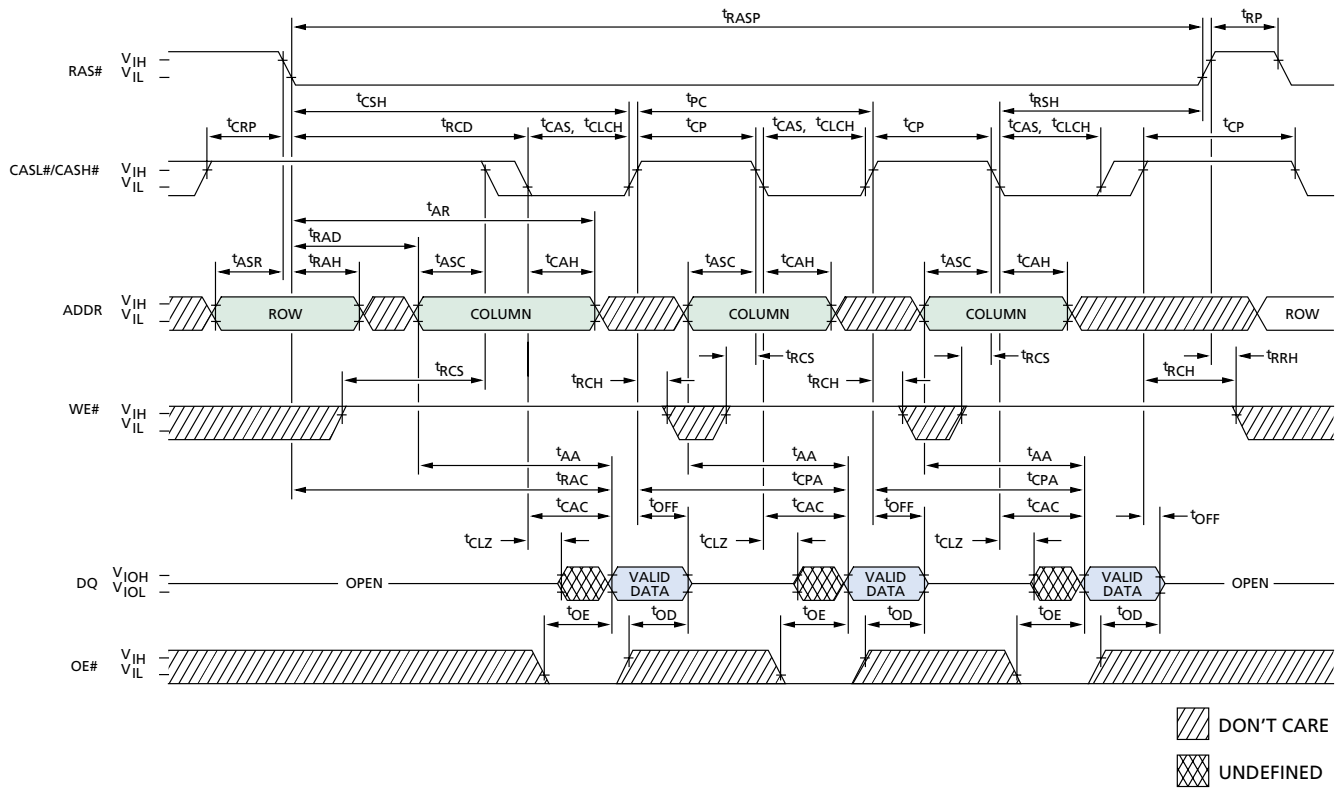
Legend:

- DON'T CARE
- UNDEFINED

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
^t AA		25		30	ns
^t AR	38		45		ns
^t ASC	0		0		ns
^t ASR	0		0		ns
^t AWD	42		49		ns
^t CAC		15		15	ns
^t CAH	8		10		ns
^t CAS	8	10,000	10	10,000	ns
^t CLCH	10		10		ns
^t CLZ	0		0		ns
^t CRP	5		5		ns
^t CSH	38		45		ns
^t CWD	28		35		ns
^t CWL	8		10		ns
^t DH	8		10		ns
^t DS	0		0		ns

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
^t OD	0	12	0	15	ns
^t OE		12		15	ns
^t OE _H	8		10		ns
^t RAC		50		60	ns
^t RAD	9		12		ns
^t RA _H	9		10		ns
^t RAS	50	10,000	60	10,000	ns
^t RCD	11		14		ns
^t RCS	0		0		ns
^t RP	30		40		ns
^t RSH	13		15		ns
^t RWC	116		140		ns
^t RWD	67		79		ns
^t RWL	13		15		ns
^t WP	5		5		ns

FAST-PAGE-MODE READ CYCLE



TIMING PARAMETERS

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t _{AA}		25		30	ns
t _{AR}	38		45		ns
t _{ASC}	0		0		ns
t _{ASR}	0		0		ns
t _{CAC}		15		15	ns
t _{CAH}	8		10		ns
t _{CAS}	8	10,000	10	10,000	ns
t _{CLCH}	10		10		ns
t _{CLZ}	0		0		ns
t _{CP}	8		5		ns
t _{CPA}		28		35	ns
t _{CRP}	5		5		ns
t _{CSH}	38		45		ns
t _{OD}	0	12	0	15	ns

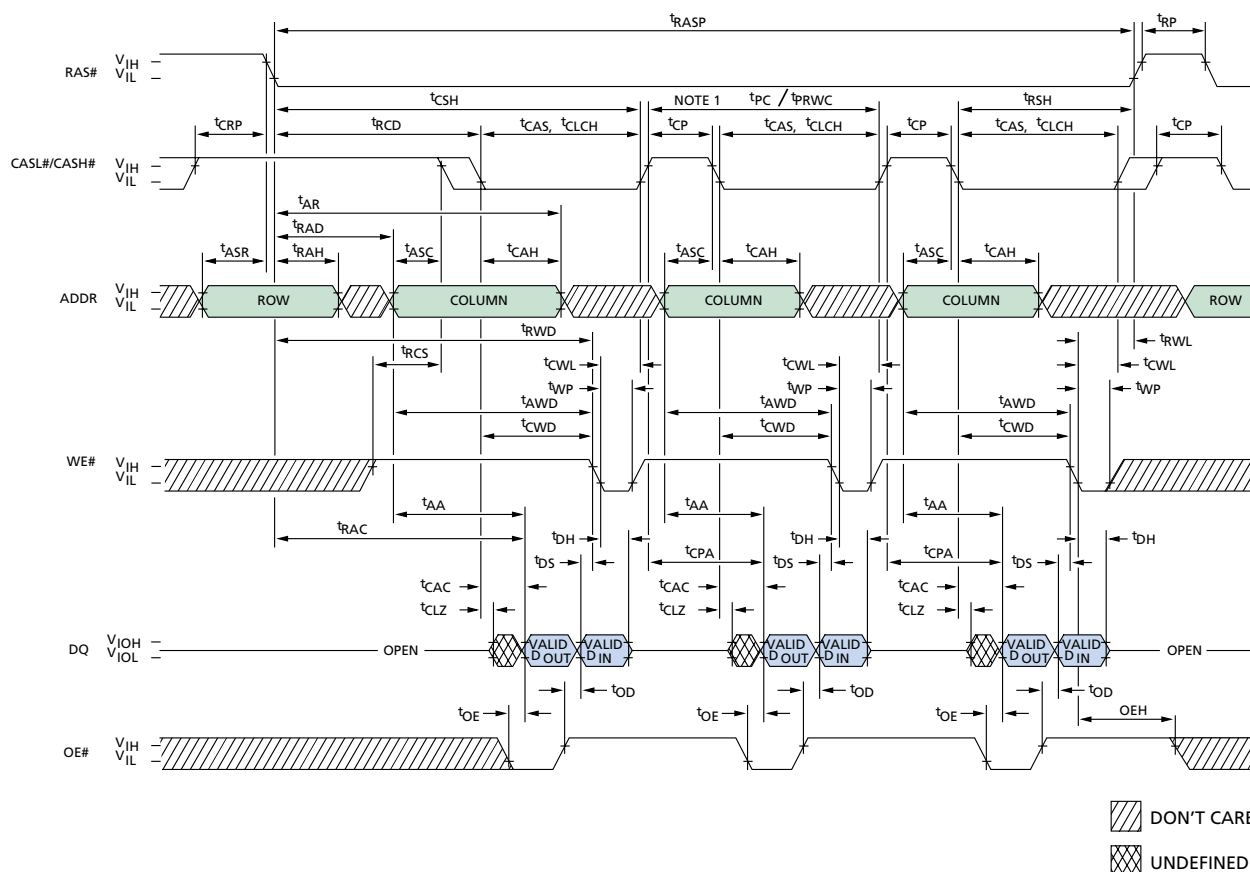
SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t _{OE}		12		15	ns
t _{OFF}	0	12	0	15	ns
t _{PC}	20		25		ns
t _{RAC}		50		60	ns
t _{RAD}	9		12		ns
t _{RAH}	9		10		ns
t _{RASP}	50	125,000	60	125,000	ns
t _{RCD}	11		14		ns
t _{RCH}	0		0		ns
t _{RCS}	0		0		ns
t _{RP}	30		40		ns
t _{RRH}	0		0		ns
t _{RSH}	13		15		ns

[illegible]

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
^t AR	38		45		ns
^t ASC	0		0		ns
^t ASR	0		0		ns
^t CAH	8		10		ns
^t CAS	8	10,000	10	10,000	ns
^t CLCH	10		10		ns
^t CP	8		5		ns
^t CRP	5		5		ns
^t CSH	38		45		ns
^t CWL	8		10		ns
^t DH	8		10		ns
^t DS	0		0		ns

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
^t PC	20		25		ns
^t RAD	9		12		ns
^t RAH	9		10		ns
^t RASP	50	125,000	60	125,000	ns
^t RCD	11		14		ns
^t RP	30		40		ns
^t RSH	13		15		ns
^t RWL	13		15		ns
^t WCH	8		10		ns
^t WCR	38		45		ns
^t WCS	0		0		ns
^t WP	5		5		ns

FAST-PAGE-MODE READ-WRITE CYCLE (LATE WRITE and READ-MODIFY-WRITE cycles)



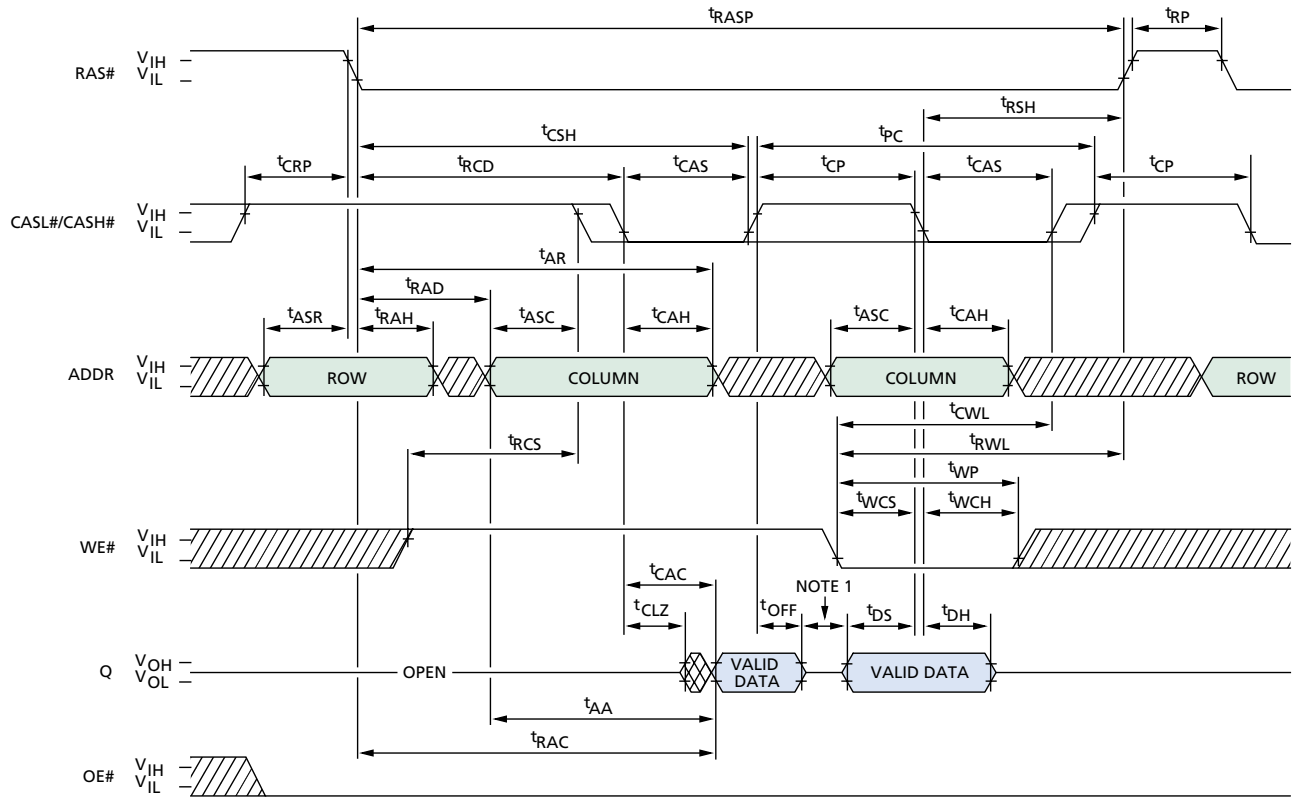
TIMING PARAMETERS

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
^t AA		25		30	ns
^t AR	38		45		ns
^t ASC	0		0		ns
^t ASR	0		0		ns
^t AWD	42		49		ns
^t CAC		15		15	ns
^t CAH	8		10		ns
^t CAS	8	10,000	10	10,000	ns
^t CLCH	10		10		ns
^t CLZ	0		0		ns
^t CP	8		5		ns
^t CPA		28		35	ns
^t CRP	5		5		ns
^t CSH	38		45		ns
^t CWD	28		35		ns
^t CWL	8		10		ns
^t DH	8		10		ns

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
^t DS	0		0		ns
^t OD	0	12	0	15	ns
^t OE		12		15	ns
^t OE _H	8		10		ns
^t PC	20		25		ns
^t PRWC	47		56		ns
^t RAC		50		60	ns
^t RAD	9		12		ns
^t RAH	9		10		ns
^t RASP	50	125,000	60	125,000	ns
^t RCD	11		14		ns
^t RCS	0		0		ns
^t RP	30		40		ns
^t RSH	13		15		ns
^t RWD	67		79		ns
^t RWL	13		15		ns
^t WP	5		5		ns

NOTE: 1. ^tPC is for LATE WRITE only.

FAST-PAGE-MODE READ EARLY WRITE CYCLE (Pseudo READ-MODIFY-WRITE)



DON'T CARE
 UNDEFINED

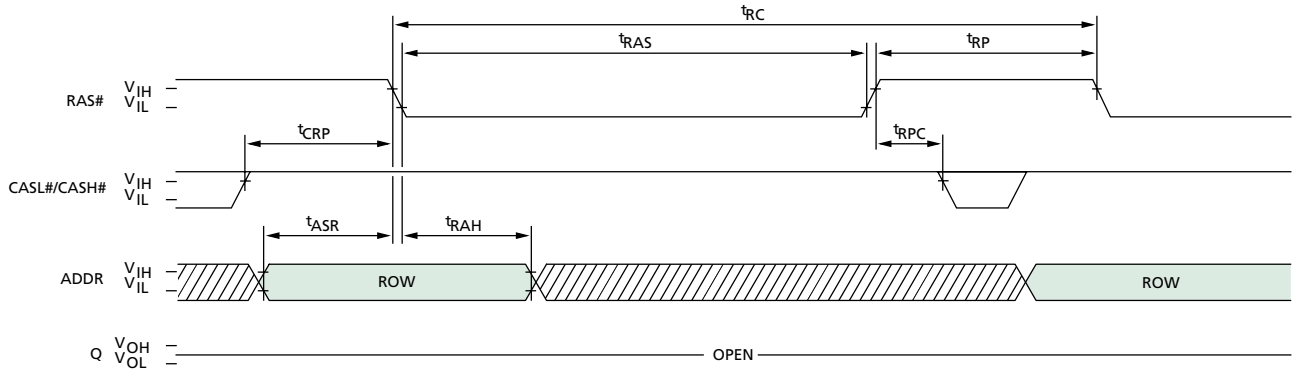
TIMING PARAMETERS

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t _{AA}		25		30	ns
t _{AR}	38		45		ns
t _{ASC}	0		0		ns
t _{ASR}	0		0		ns
t _{CAC}		15		15	ns
t _{CAH}	8		10		ns
t _{CAS}	8	10,000	10	10,000	ns
t _{CLZ}	0		0		ns
t _{CP}	8		5		ns
t _{CRP}	5		5		ns
t _{CSH}	38		45		ns
t _{CWL}	8		10		ns
t _{DH}	8		10		ns
t _{DS}	0		0		ns

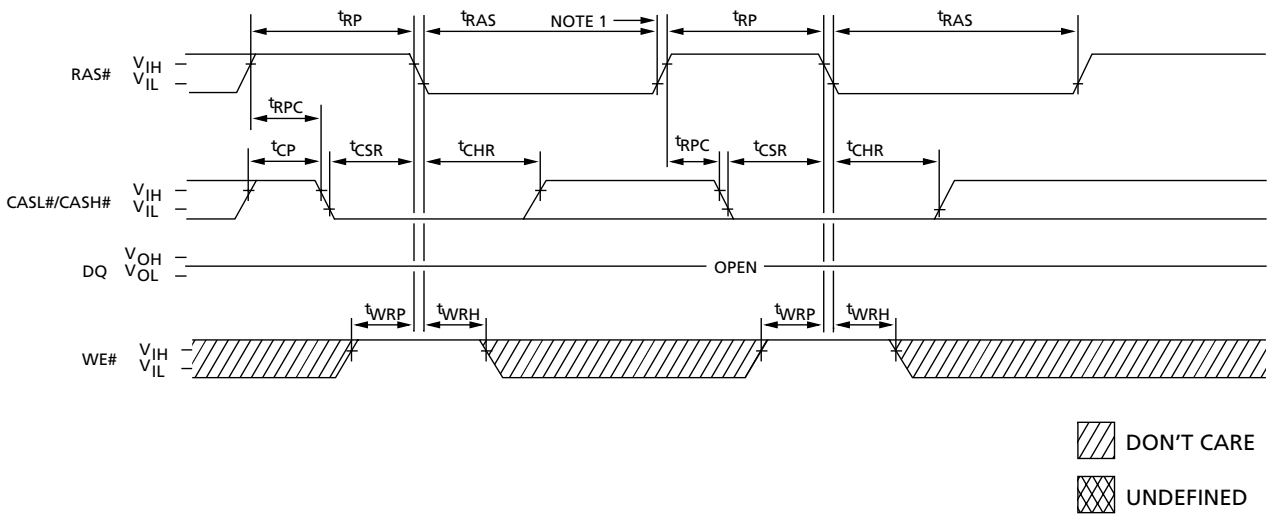
SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t _{OFF}	0	12	0	15	ns
t _{PC}	20		25		ns
t _{RAC}		50		60	ns
t _{RAD}	9		12		ns
t _{RAH}	9		10		ns
t _{RASP}	50	125,000	60	125,000	ns
t _{RCD}	11		14		ns
t _{RCS}	0		0		ns
t _{RP}	30		40		ns
t _{RSH}	13		15		ns
t _{RWL}	13		15		ns
t _{WCH}	8		10		ns
t _{WCS}	0		0		ns
t _{WP}	5		5		ns

NOTE: 1. t_{PC} is for LATE WRITE only.

RAS#-ONLY REFRESH CYCLE (OE# and WE# = DON'T CARE)



CBR REFRESH CYCLE (Addresses and OE# = DON'T CARE)



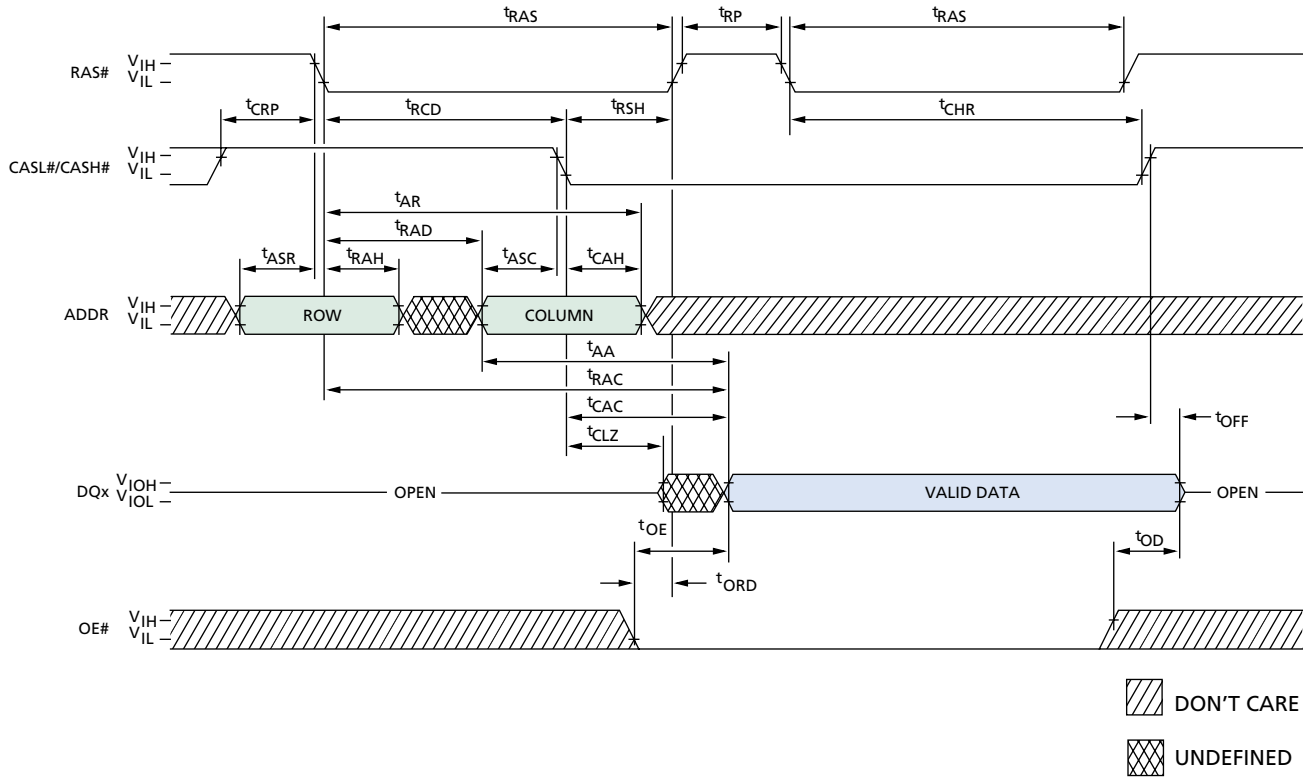
TIMING PARAMETERS

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{ASr}	0		0		ns
t_{CHR}	8		10		ns
t_{CP}	8		5		ns
t_{CRP}	5		5		ns
t_{CSR}	5		5		ns
t_{RAH}	9		10		ns

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{RAS}	50		60	10,000	ns
t_{RC}	84		104		ns
t_{RP}	30		40		ns
t_{RPC}	5		5		ns
t_{WRH}	8		10		ns
t_{WRP}	8		10		ns

NOTE: 1. End of CBR REFRESH cycle.

HIDDEN REFRESH CYCLE¹ (WE# = HIGH; OE# = LOW)



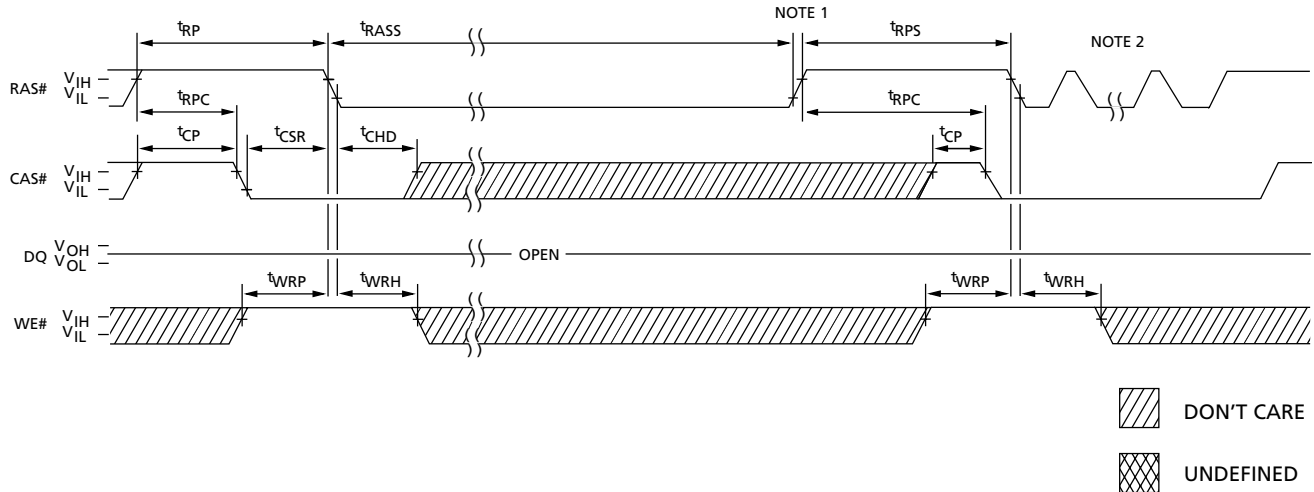
TIMING PARAMETERS

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t _{AA}		25		30	ns
t _{AR}	38		45		ns
t _{ASC}	0		0		ns
t _{ASR}	0		0		ns
t _{CAC}		15		15	ns
t _{CAH}	8		10		ns
t _{CHR}	8		10		ns
t _{CLZ}	0		0		ns
t _{CRP}	5		5		ns
t _{OD}	0	12	0	15	ns

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t _{OE}		12		15	ns
t _{OFF}	0	12	0	15	ns
t _{ORD}	0		0		ns
t _{RAC}		50		60	ns
t _{RAD}	9		12		ns
t _{RAH}	9		10		ns
t _{RAS}	50	10,000	60	10,000	ns
t _{RCD}	11		14		ns
t _{RP}	30		40		ns
t _{RSH}	13		15		ns

NOTE: 1. A HIDDEN REFRESH may also be performed after a WRITE cycle. In this case, WE# is LOW and OE# is HIGH.

SELF REFRESH CYCLE (Addresses and OE# = DON'T CARE)

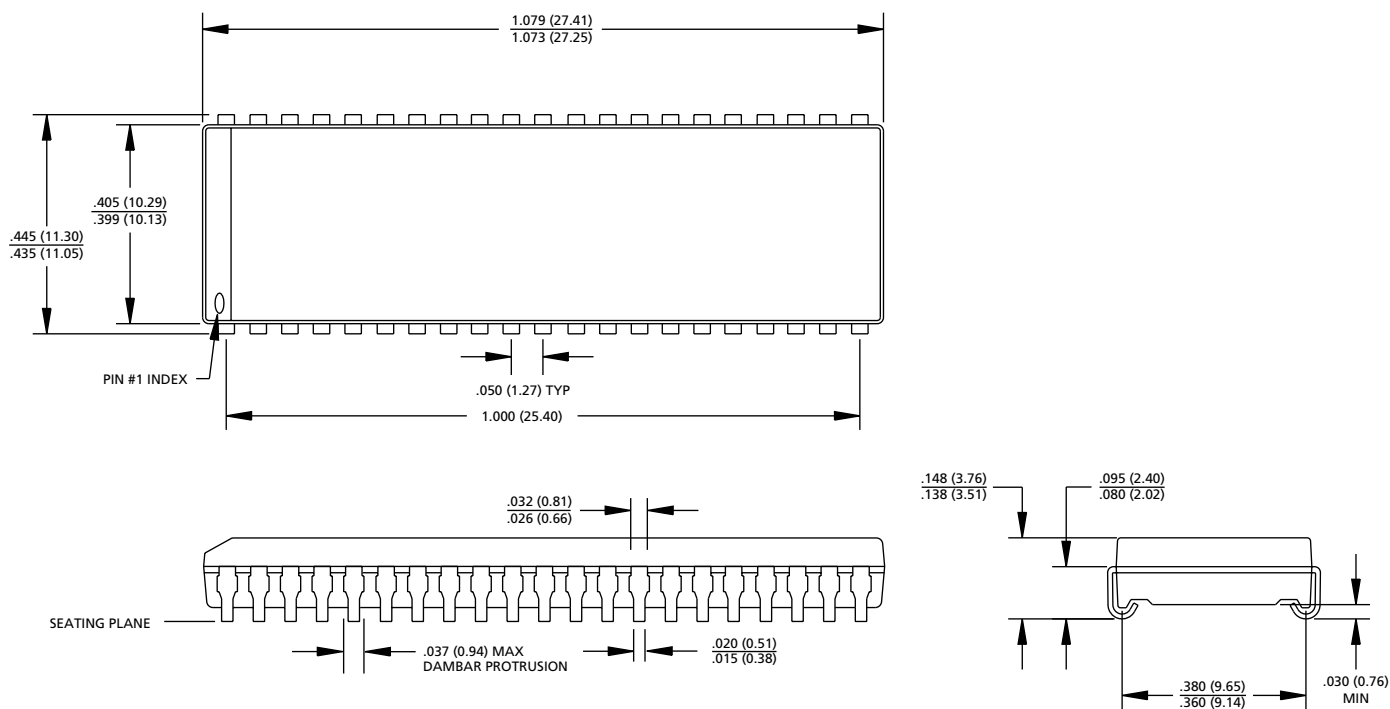


TIMING PARAMETERS

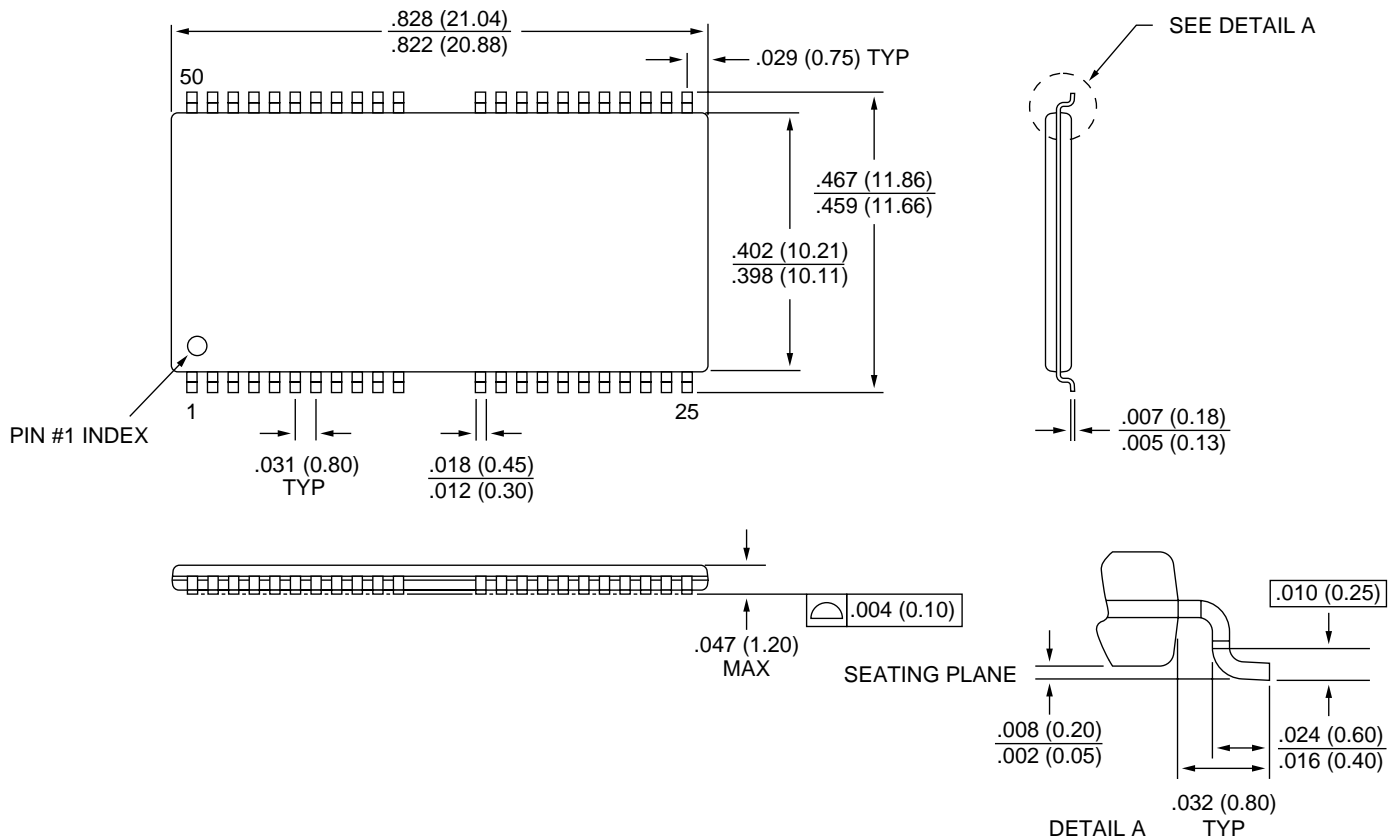
SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{CHD}	15		15		ns
t_{CLCH}	10		10		ns
t_{CP}	8		5		ns
t_{CSR}	5		5		ns
t_{RASS}	100		100		μ s

SYMBOL	-5		-6		UNITS
	MIN	MAX	MIN	MAX	
t_{RP}	30		40		ns
t_{RPC}	5		5		ns
t_{RPS}	90		105		ns
t_{WRH}	8		10		ns
t_{WRP}	8		10		ns

NOTE: 1. Once t_{RASS} (MIN) is met and RAS# remains LOW, the DRAM will enter self refresh mode.
2. Once t_{RPS} is satisfied, a complete burst of all rows should be executed if RAS#-only or burst CBR refresh is used.

42-PIN PLASTIC SOJ (400 mil)


- NOTE:**
1. All dimensions in inches (millimeters) $\frac{\text{MAX}}{\text{MIN}}$ or typical where noted.
 2. Package width and length do not include mold protrusion; allowable mold protrusion is .01" per side.

44/50-PIN PLASTIC TSOP (400 mil)


- NOTE:**
1. All dimensions in inches (millimeters) $\frac{\text{MAX}}{\text{MIN}}$ or typical where noted.
 2. Package width and length do not include mold protrusion; allowable mold protrusion is .01" per side.



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